

General Description:

The LWD3001AD3 uses trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is PDFN3.3*3.3-8L, which accords with the ROHS standard and Halogen Free standard.

Features:

- Fast Switching
- Low Gate Charge and $R_{DS(ON)}$
- Low Reverse transfer capacitances

Applications:

- DC-DC Converter
- Portable Equipment
- Power Management

100% DVDS Tested

100% Avalanche Tested



Package Marking and Ordering Information:

Marking	Part Number	Package	Packing	Qty.
D3001A/LW D3/D.C.	LWD3001AD3	PDFN3.3*3.3-8L	Reel	5000 Pcs

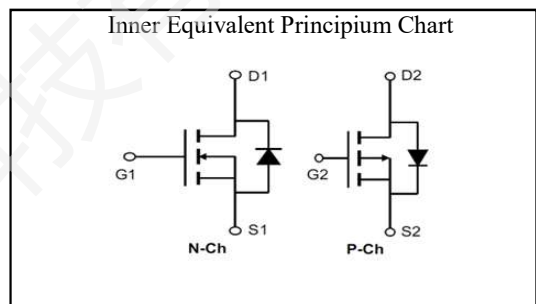
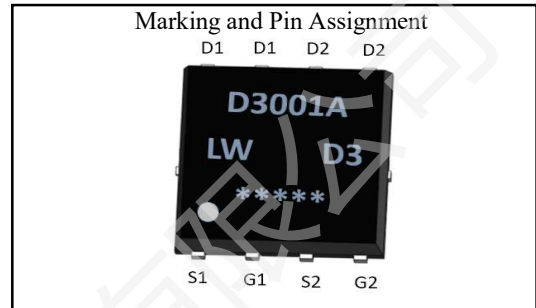
Absolute Maximum Ratings:

Symbol	Parameter		Value		Units
			N-Ch	P-Ch	
V _{DSS}	Drain-to-Source Voltage		30	-30	V
I _D	Continuous Drain Current	T _C =25°C	30	-28	A
	Continuous Drain Current	T _C =100°C	19	-18	A
I _{DM} ^{a1}	Pulsed Drain Current		120	-112	A
E _{AS} ^{a2}	Single pulse avalanche energy		45	48	mJ
V _{GS}	Gate-to-Source Voltage		±20	±20	V
P _D	Power Dissipation		18	18	W
T _J , T _{STG}	Operating Junction and Storage Temperature Range		150, -55 to 150		°C
T _L	Maximum Temperature for Soldering		260		°C

Thermal Characteristics:

Symbol	Parameter	Value		Units
		N-Ch	P-Ch	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	6.9	6.9	$^{\circ}C/W$
$R_{\theta JA}^{a3}$	Thermal Resistance, Junction-to-Ambient	45	45	$^{\circ}C/W$

Symbol	N-Ch	P-Ch	Units
V_{DSS}	30	-30	V
I_D	30	-28	A
$R_{DS(ON) \text{ TYPE}}$	6.5	14	m Ω



N-Channel Electrical Characteristic ($T_C = 25\text{ }^{\circ}\text{C}$, unless otherwise specified):

Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	--	--	V
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=30V, V_{GS}=0V$	--	--	1.0	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V, V_{DS}=0V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V, V_{DS}=0V$	--	--	-100	nA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.0	V
$R_{DS(ON)1}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=15A$	--	6.5	9.5	$m\Omega$
$R_{DS(ON)2}$	Drain-to-Source On-Resistance	$V_{GS}=4.5V, I_D=8A$	--	9.0	13	$m\Omega$

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C_{iss}	Input Capacitance	$V_{GS} = 0V$	--	1237	--	pF
C_{oss}	Output Capacitance	$V_{DS} = 15V$	--	180	--	
C_{rss}	Reverse Transfer Capacitance	$f = 1.0MHz$	--	160	--	
R_G	Gate resistance	$V_{GS}=0V, V_{DS}=0V, f=1.0MHz$	--	1.7	--	Ω

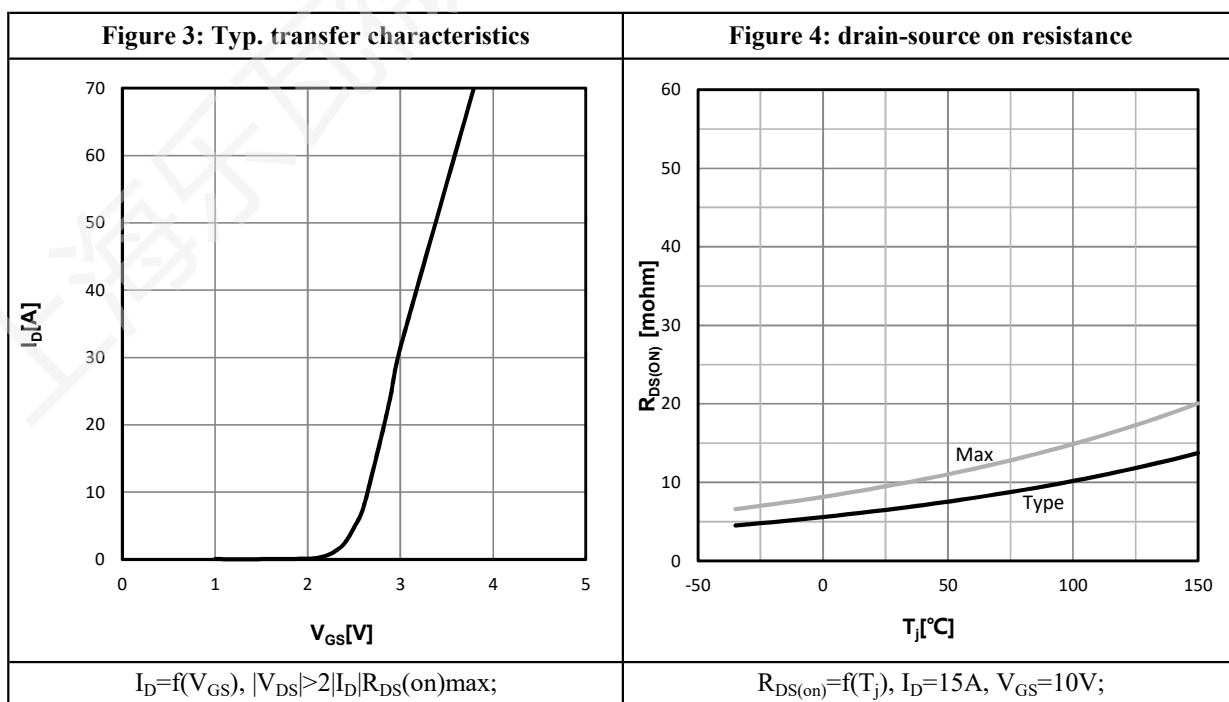
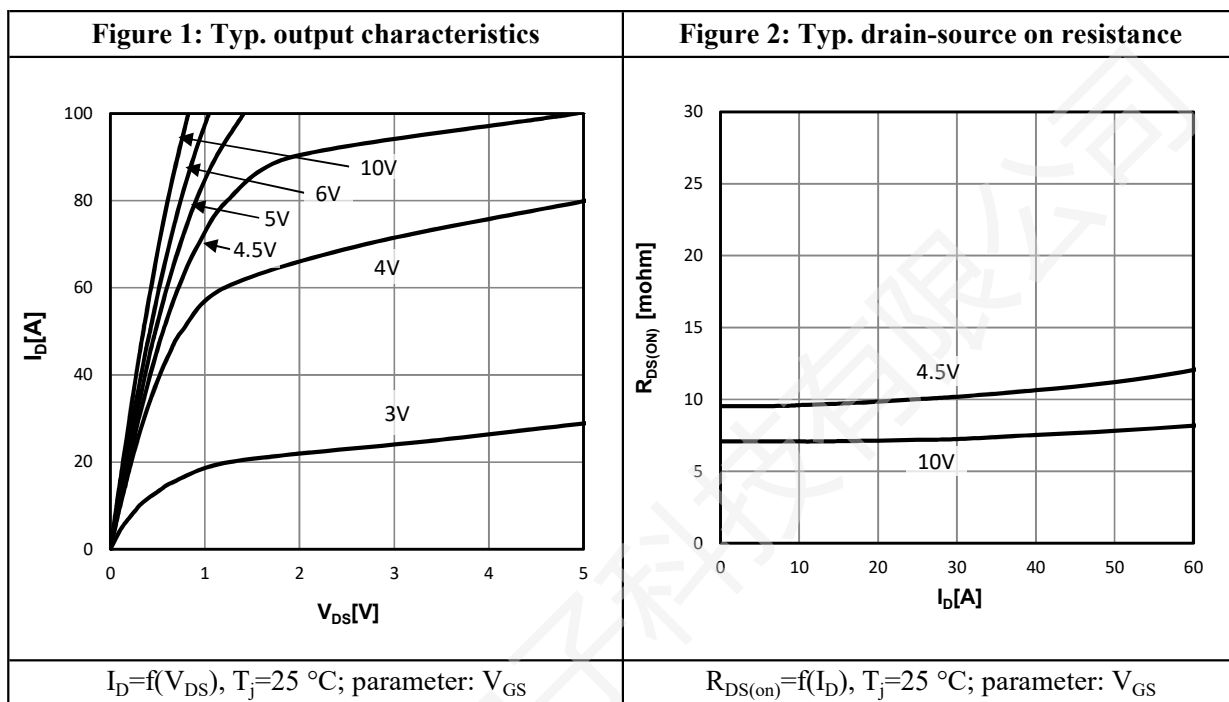
Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 15A$	--	5.0	--	ns
t_r	Rise Time	$V_{DS} = 15V$	--	11	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS} = 10V$	--	13	--	
t_f	Fall Time	$R_G = 3.0\Omega$	--	6.0	--	
Q_g	Total Gate Charge	$V_{GS} = 10V$	--	30	--	nC
Q_{gs}	Gate Source Charge	$V_{DS} = 15V$	--	4.0	--	
Q_{gd}	Gate Drain Charge	$I_D = 15A$	--	8.1	--	

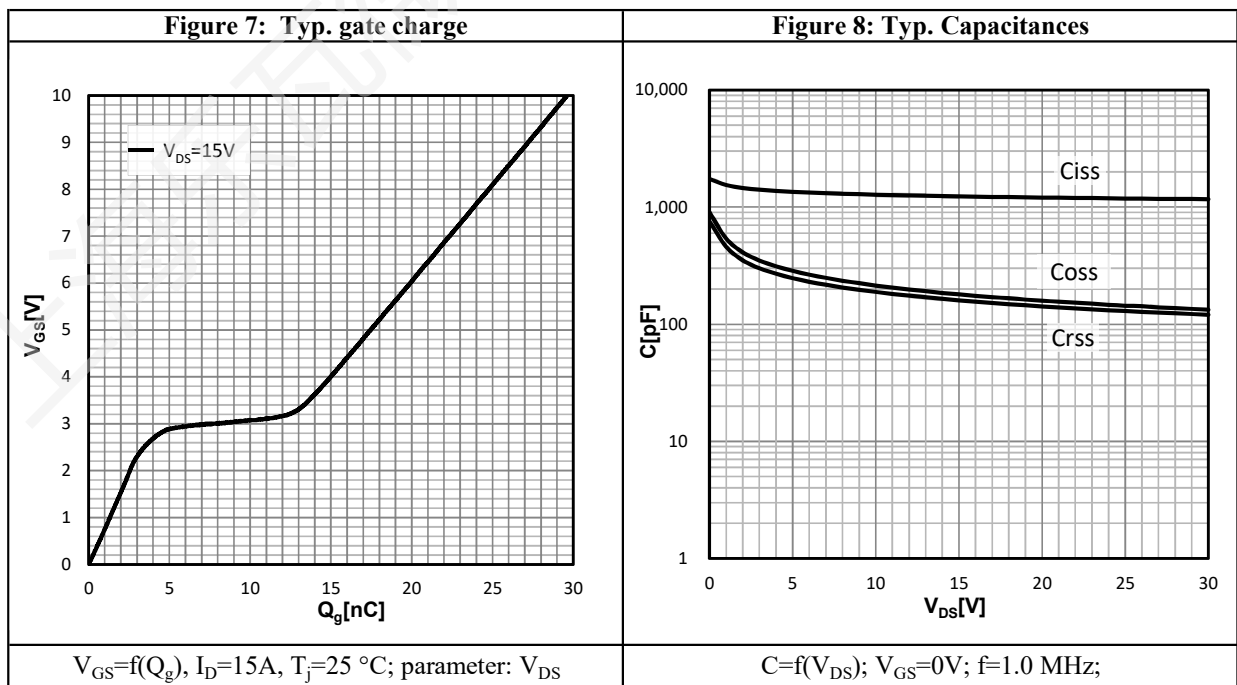
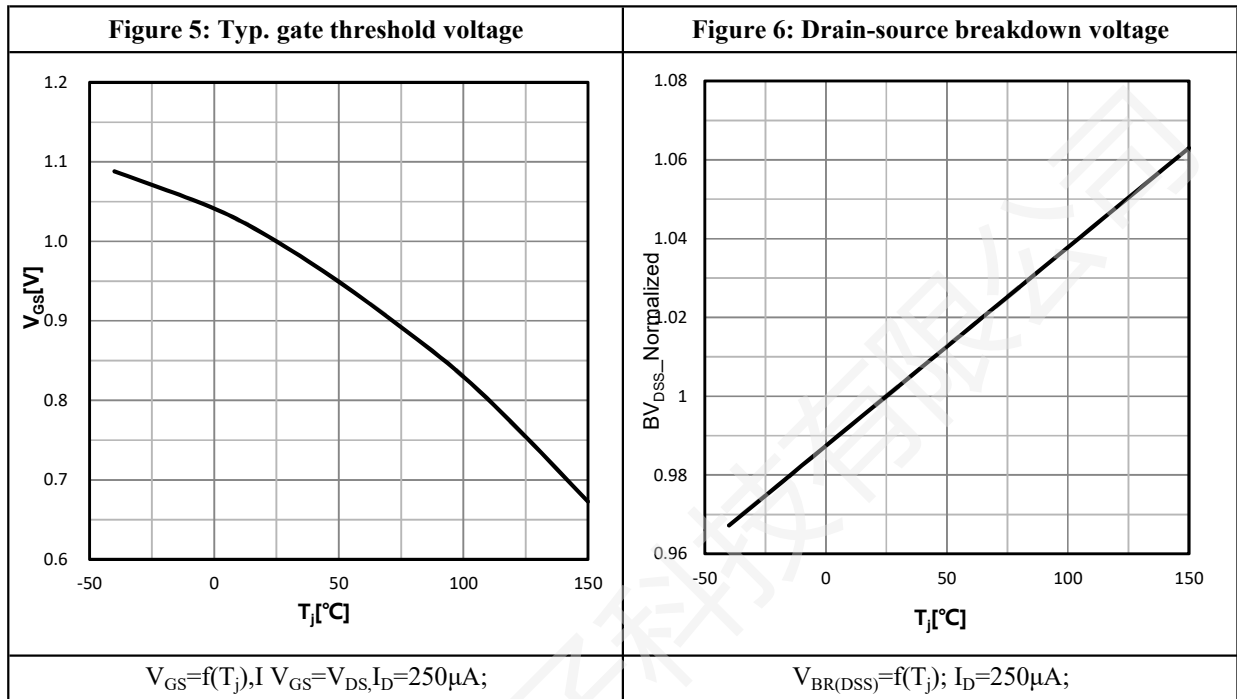
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
I_S	Diode Forward Current	$T_C = 25\text{ }^{\circ}\text{C}$	--	--	30	A
V_{SD}	Diode Forward Voltage	$I_S=15A, V_{GS}=0V$	--	--	1.2	V

a1: Repetitive rating; pulse width limited by maximum junction temperature

a2: $V_{DD}=15V, L=0.1mH, R_G=25\Omega$, Starting $T_J=25\text{ }^{\circ}\text{C}$

a3: Surface Mounted on FR4 Board, $t \leq 10sec$

N-Channel Characteristics Curve:




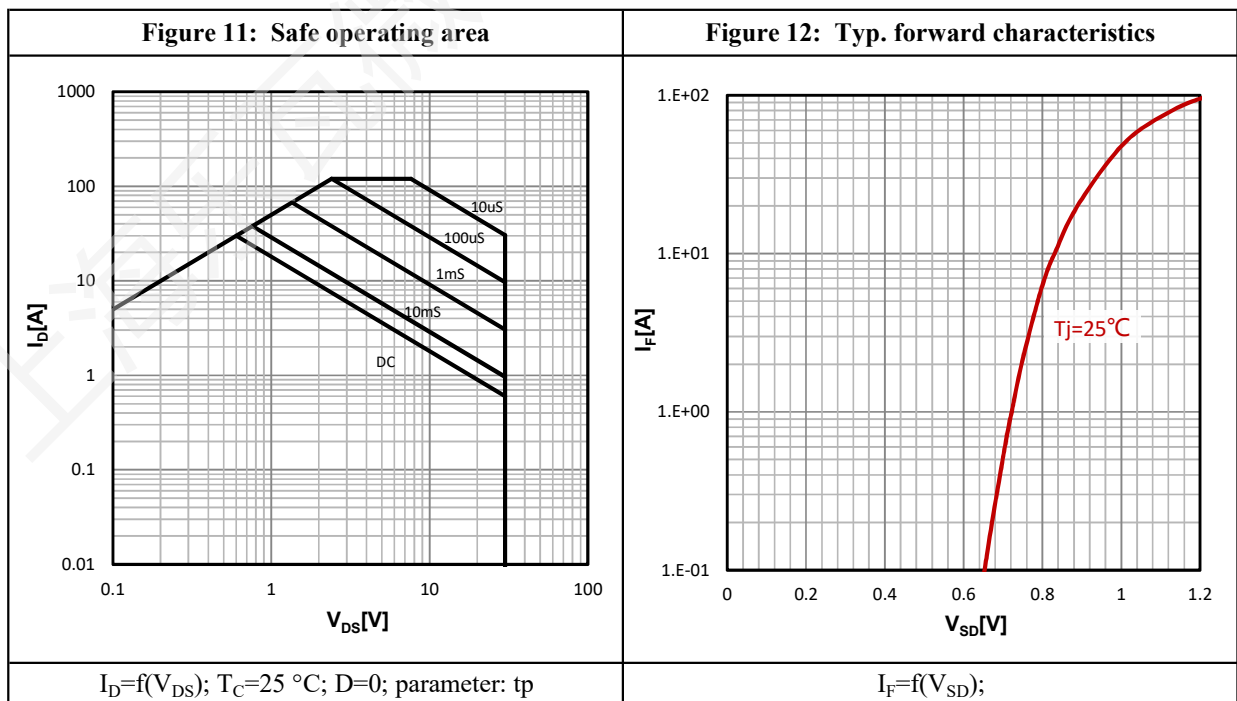
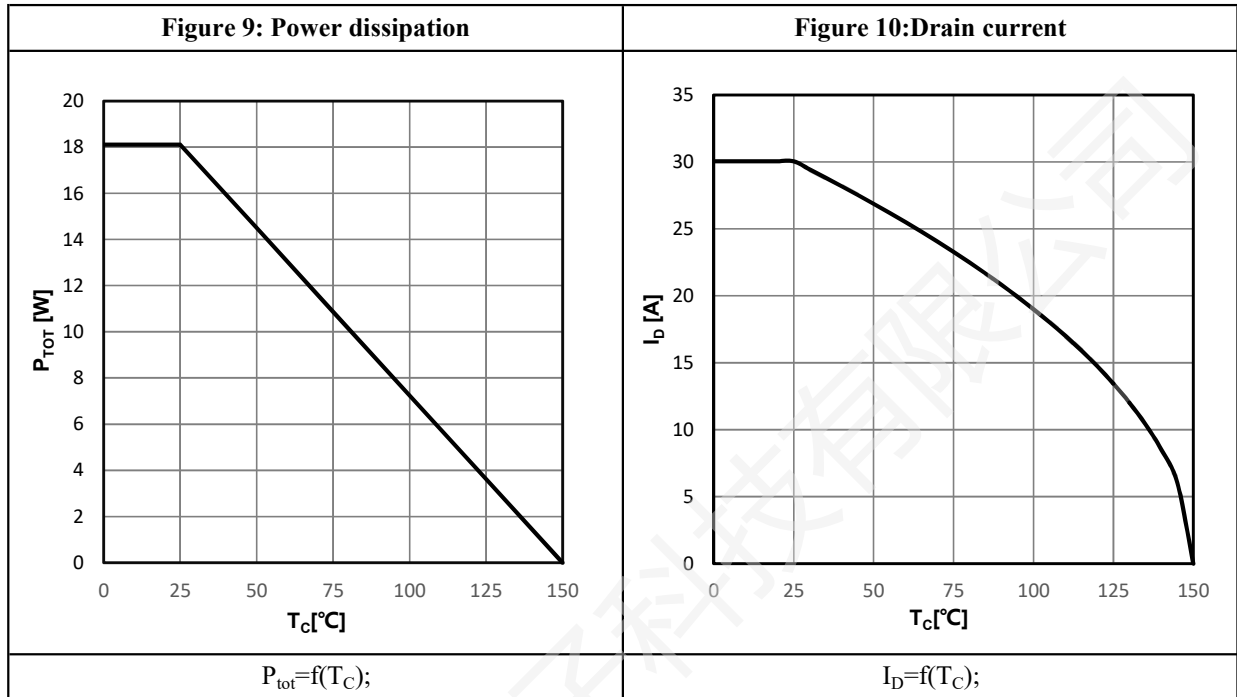
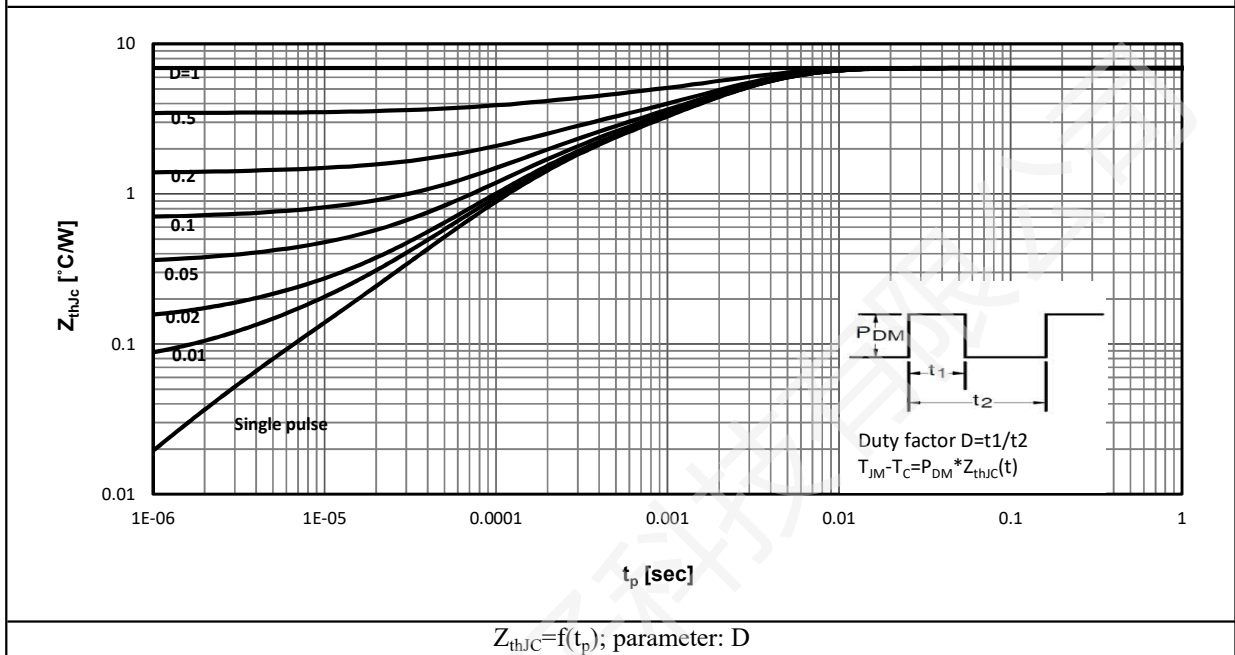
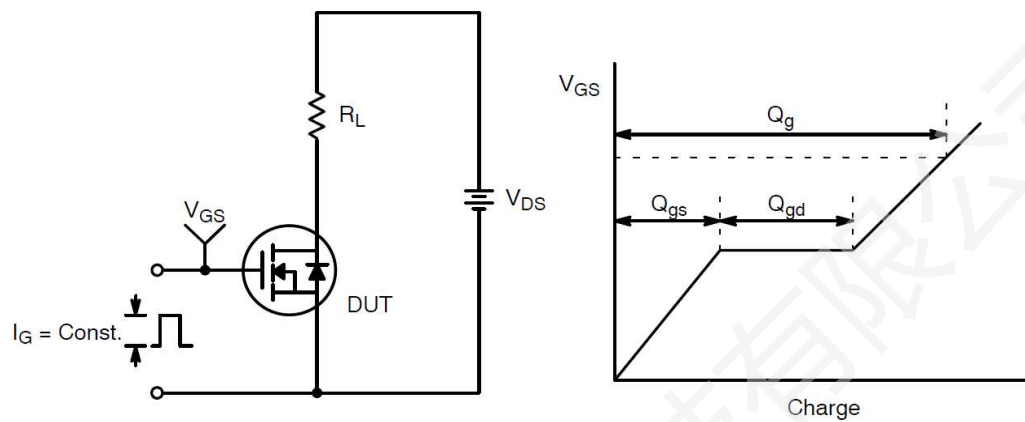
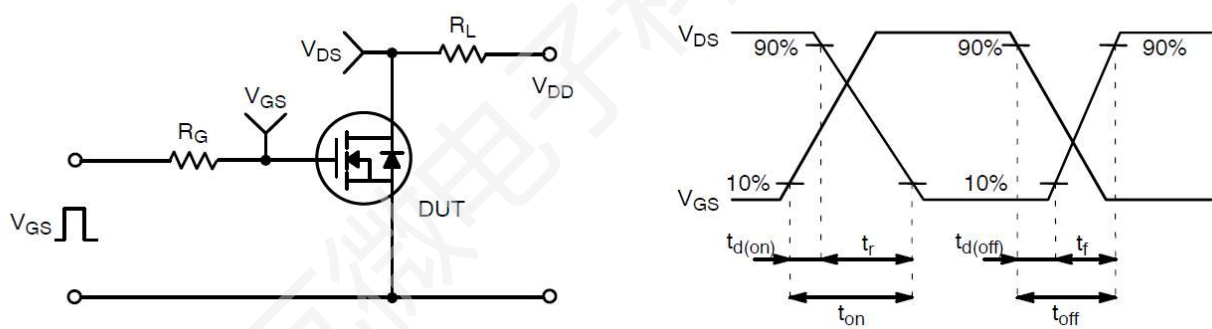
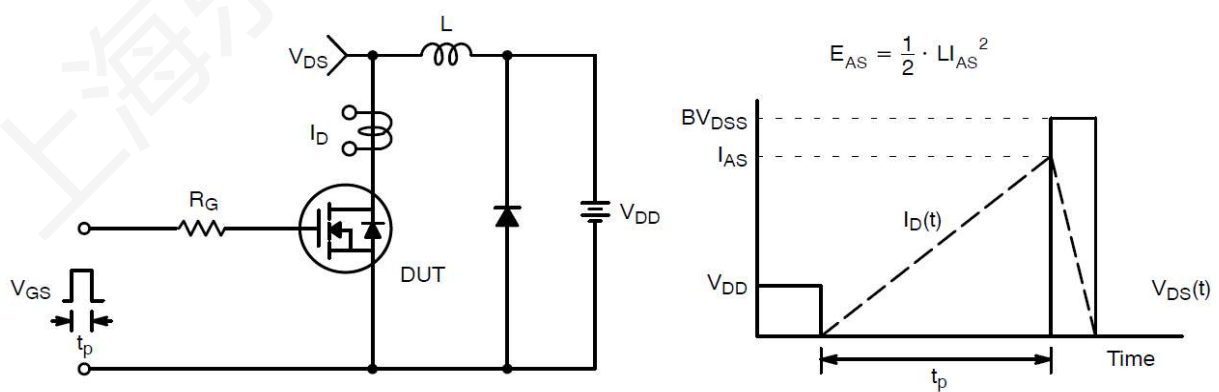


Figure 13: Max. Transient Thermal Impedance


Test Circuit & Waveform:

Figure 14: Gate Charge Test Circuit & Waveform

Figure 15: Resistive Switching Test Circuit & Waveforms

Figure 16: Unclamped Inductive Switching Test Circuit & Waveforms

P-Channel Electrical Characteristic ($T_C = 25\text{ }^{\circ}\text{C}$, unless otherwise specified):

Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	--	--	V
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=-30V, V_{GS}=0V$	--	--	1.0	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=-20V, V_{DS}=0V$	--	--	-100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=+20V, V_{DS}=0V$	--	--	100	nA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.2	-1.6	-2.0	V
$R_{DS(ON)1}$	Drain-to-Source On-Resistance	$V_{GS}=-10V, I_D=-10A$	--	14	19	$m\Omega$
$R_{DS(ON)2}$	Drain-to-Source On-Resistance	$V_{GS}=-4.5V, I_D=-5.0A$	--	19	30	$m\Omega$

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C_{iss}	Input Capacitance	$V_{GS} = 0V$	--	1243	--	pF
C_{oss}	Output Capacitance	$V_{DS} = -15V$	--	186	--	
C_{rss}	Reverse Transfer Capacitance	$f = 1.0MHz$	--	177	--	
R_G	Gate resistance	$V_{GS}=0V, V_{DS}=0V, f=1.0MHz$	--	10	--	Ω

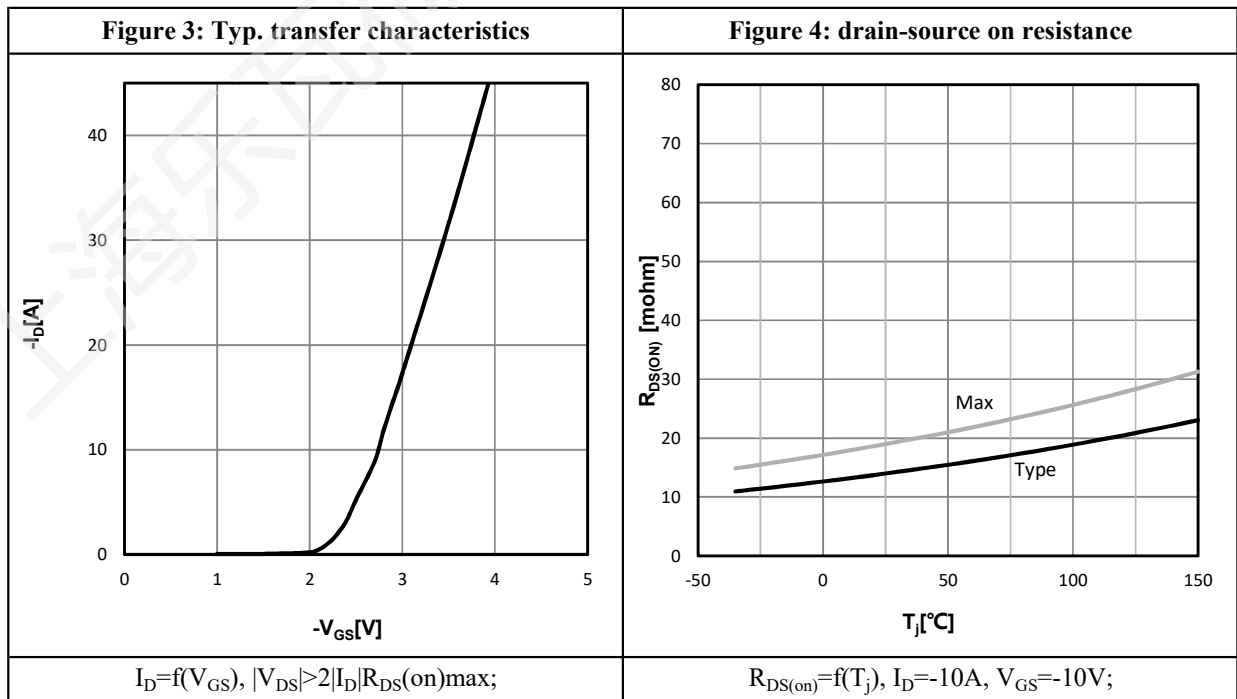
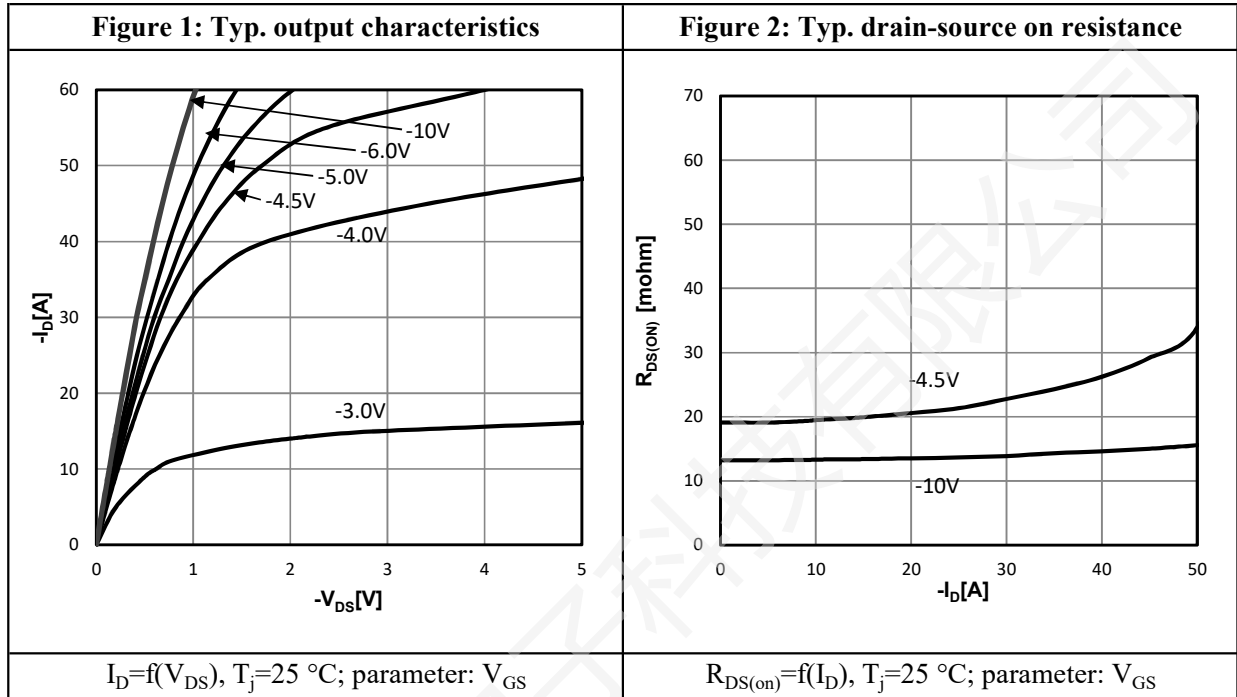
Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = -10A$	--	15	--	ns
t_r	Rise Time	$V_{DS} = -15V$	--	23	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS} = -10V$	--	40	--	
t_f	Fall Time	$R_G = 3.0\Omega$	--	11	--	
Q_g	Total Gate Charge	$V_{GS} = -10V$	--	28	--	nC
Q_{gs}	Gate to Source Charge	$V_{DS} = -15V$	--	3.3	--	
Q_{gd}	Gate to Drain Charge	$I_D = -10A$	--	6.0	--	

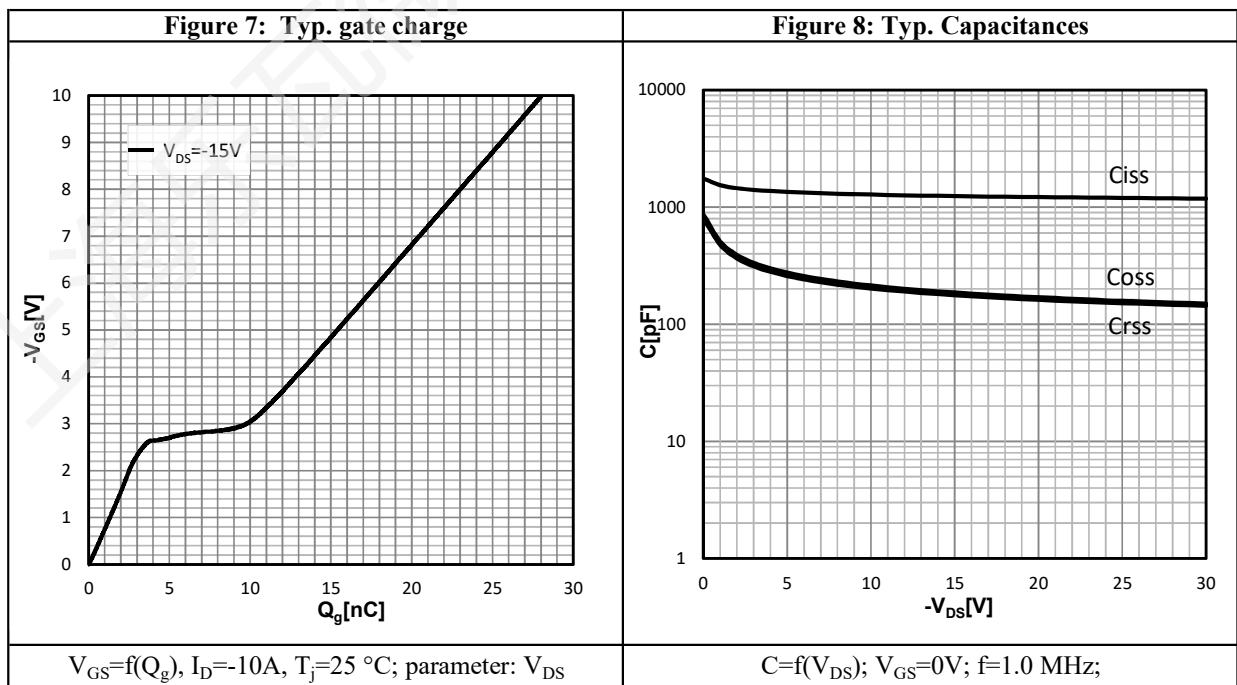
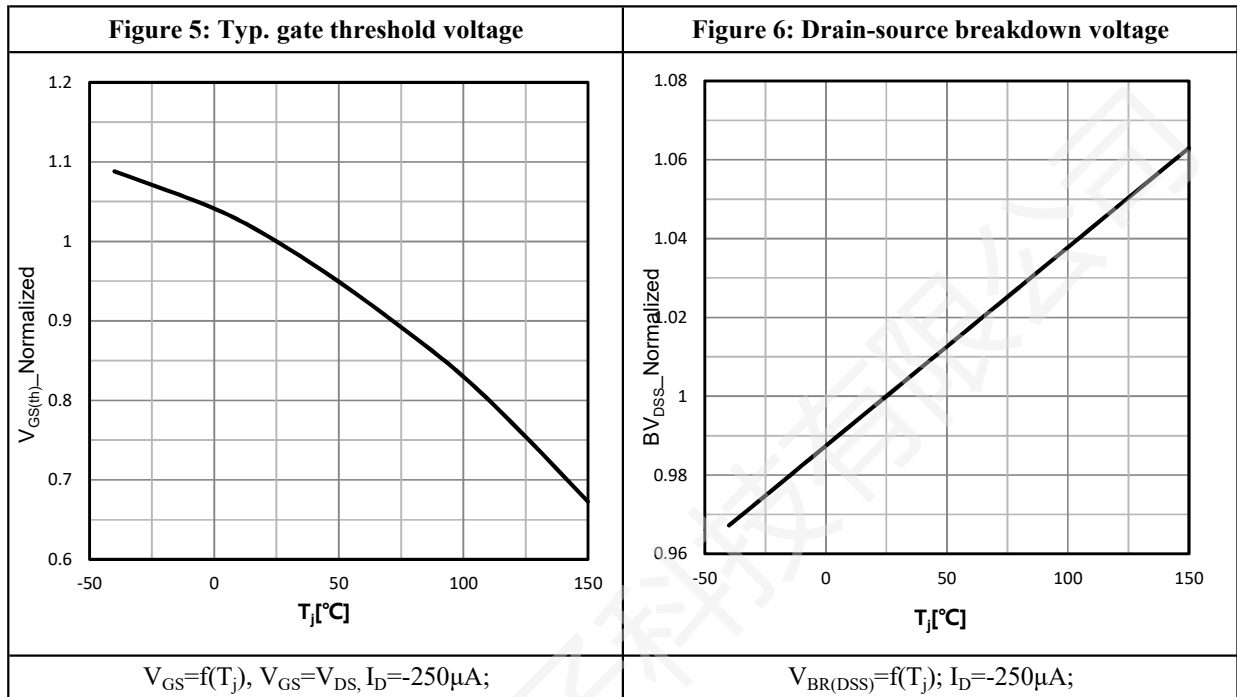
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
I_S	Diode Forward Current	$T_C = 25\text{ }^{\circ}\text{C}$	--	--	-28	A
V_{SD}	Diode Forward Voltage	$I_S = -10A, V_{GS} = 0V$	--	--	-1.2	V

a1: Repetitive rating; pulse width limited by maximum junction temperature

a2: $V_{DD} = -15V, L = 0.1mH, R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$

a3: Surface Mounted on FR4 Board, $t \leq 10\text{sec}$

P-Channel Characteristics Curve:




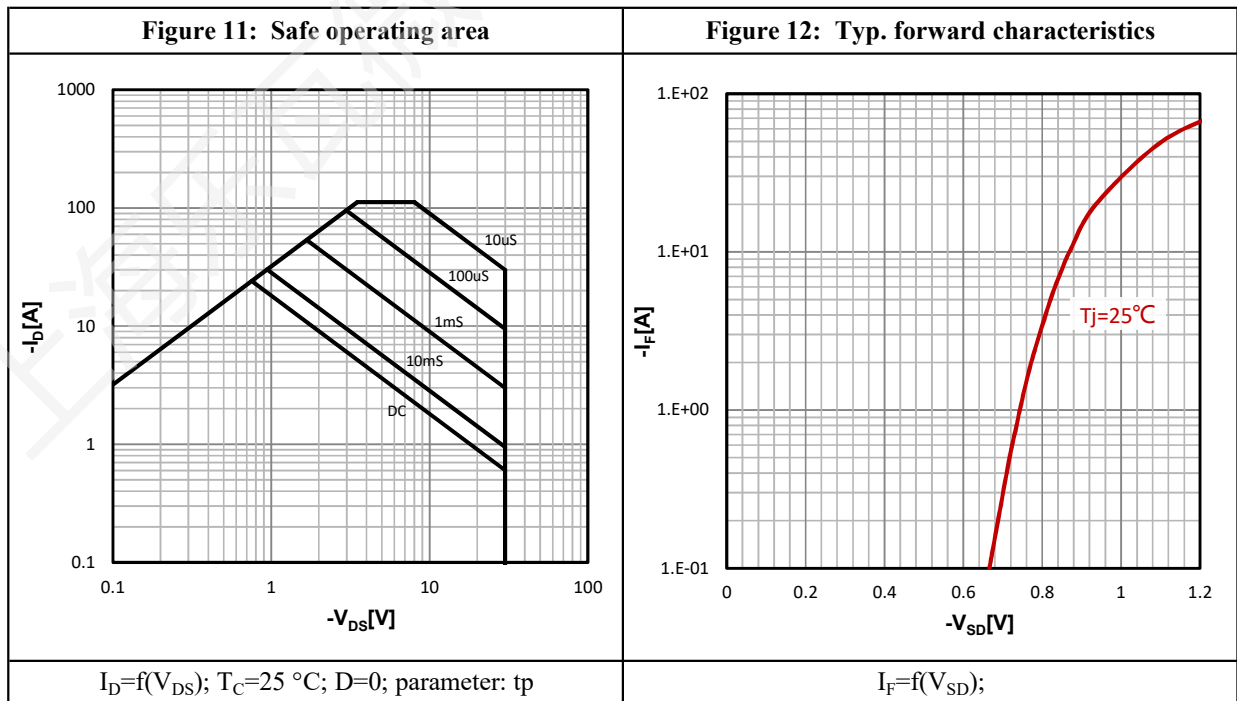
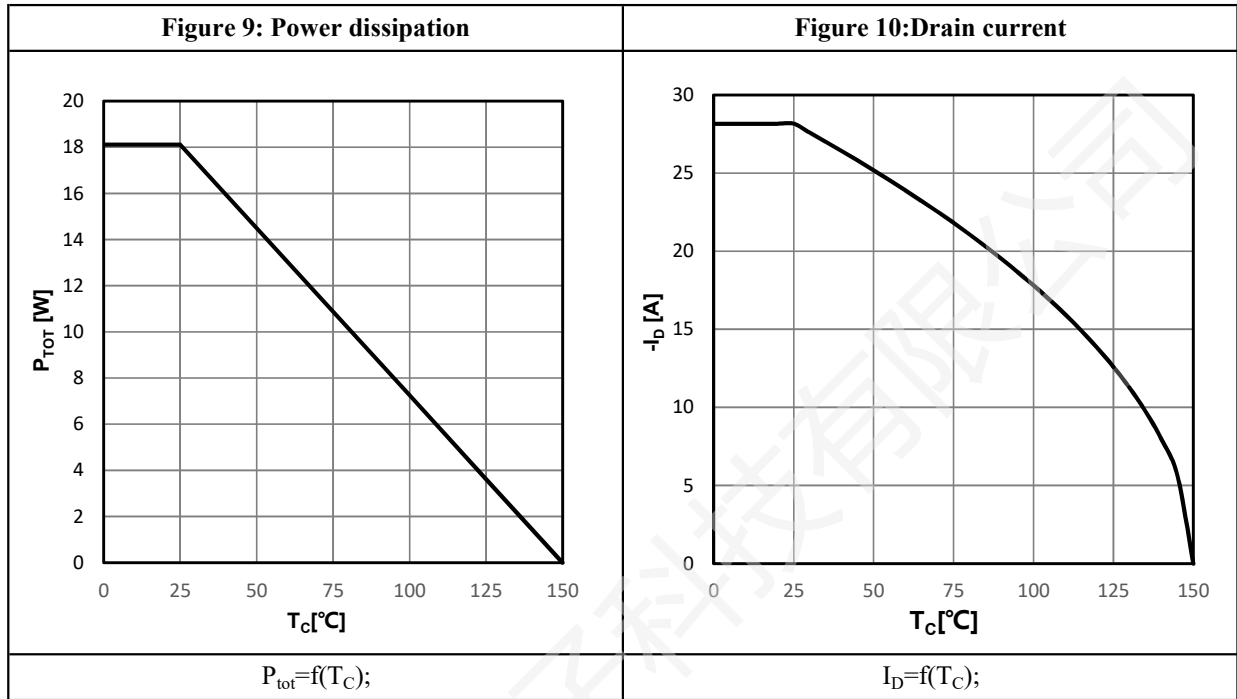
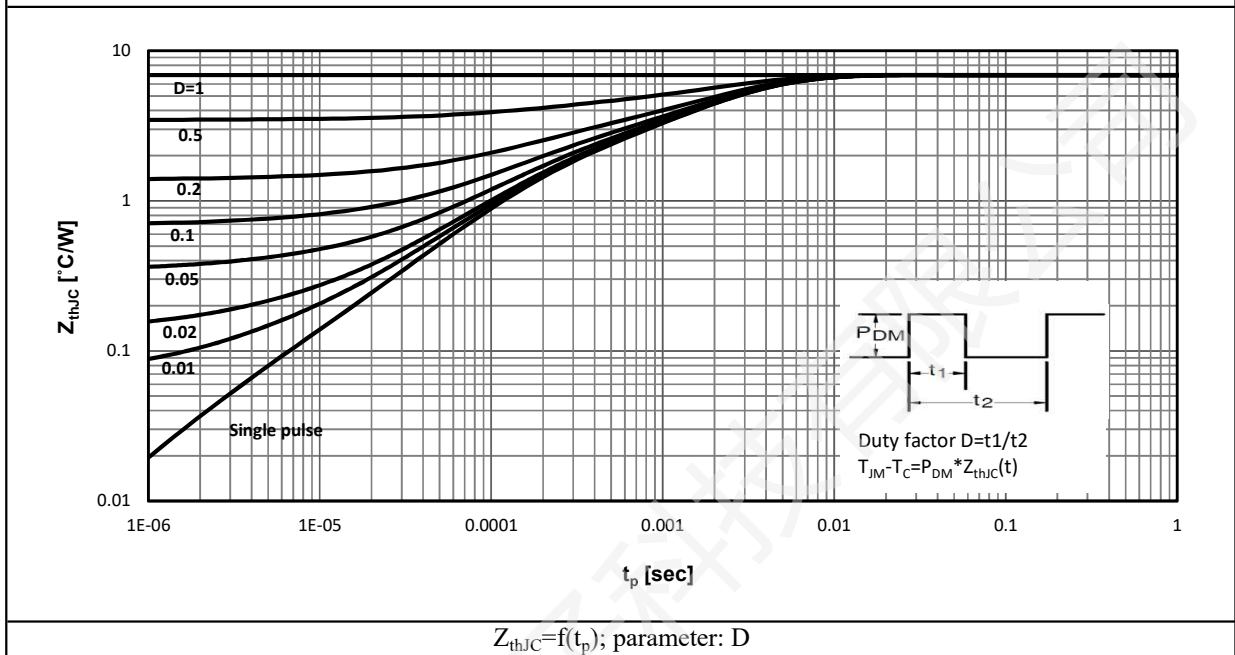


Figure 13: Max. Transient Thermal Impedance


P-Channel Test Circuit & Waveform:

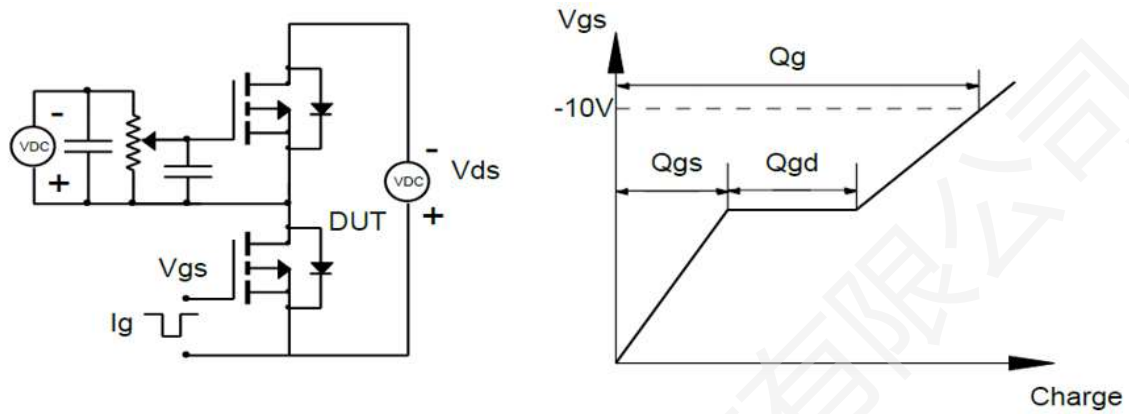


Figure 14: Gate Charge Test Circuit & Waveform

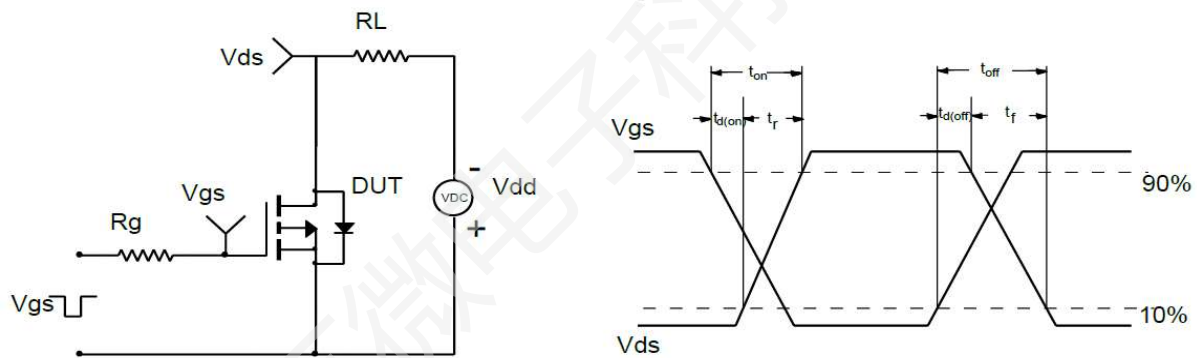


Figure 15: Resistive Switching Test Circuit & Waveforms

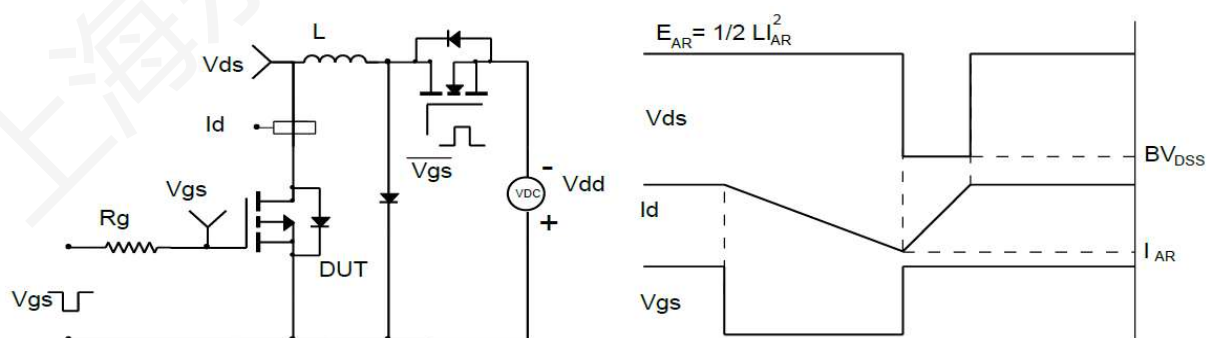
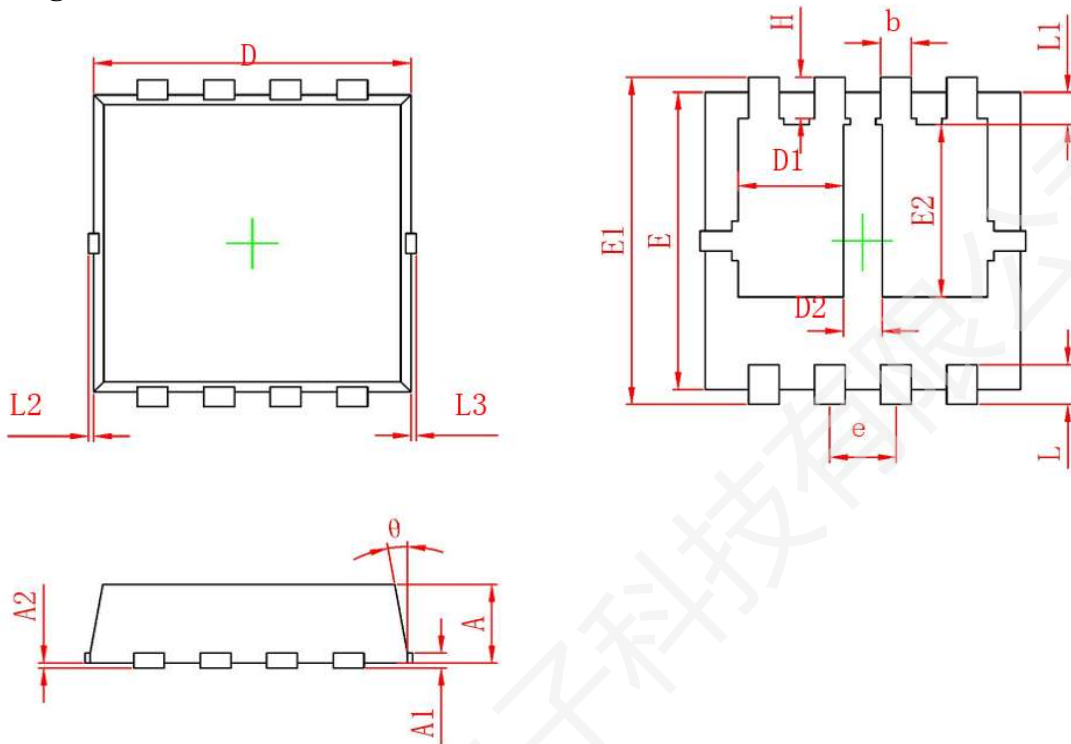


Figure 16: Unclamped Inductive Switching Test Circuit & Waveforms

Package Outline:


Symbol	MILLIMETER	
	MIN	MIN
A	0.700	0.900
A1	0.152 REF	
A2	0~0.05	
D	3.000	3.200
D1	0.935	1.135
D2	0.280	0.480
E	2.900	3.100
E1	3.150	3.450
E2	1.535	1.935
b	0.200	0.400
e	0.550	0.750
L	0.300	0.500
L1	0.180	0.480
L2	0~0.100	
L3	0~0.100	
H	0.315	0.515
θ	8°	12°

Revision History:

Revision	Date	Descriptions
Rev 1.1	Jun.2025	Initial Version

Disclaimer:

The information in this document is believed to be accurate and reliable. However, no responsibility is assumed by LW-Micro for its use. All operating parameters must be designed, validated and tested to ensure they meet the requirements of your application. LW-Micro reserves the right to make any specification and/or circuitry changes without prior notification. Before starting a brand-new project, please contact LW-Micro Sales to get the most recent relevant information.

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